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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	31775
Number of Logic Elements/Cells	406720
Total RAM Bits	29306880
Number of I/O	400
Number of Gates	-
Voltage - Supply	0.97V ~ 1.03V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 100°C (TJ)
Package / Case	676-BBGA, FCBGA
Supplier Device Package	676-FCBGA (27x27)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xc7k410t-3fbg676e

Table 5: Maximum Allowed AC Voltage Overshoot and Undershoot for 1.8V HP I/O Banks⁽¹⁾⁽²⁾ (Cont'd)

AC Voltage Overshoot	% of UI @-40°C to 100°C	AC Voltage Undershoot	% of UI @-40°C to 100°C
$V_{CCO} + 0.80$	9.71	-0.80	50.0
$V_{CCO} + 0.85$	4.51	-0.85	28.4
$V_{CCO} + 0.90$	2.12	-0.90	12.7
$V_{CCO} + 0.95$	1.01	-0.95	5.79

Notes:

1. A total of 200 mA per bank should not be exceeded.
2. For UI smaller than 20 μ s.

Table 6: Typical Quiescent Supply Current

Symbol	Description	Device	Speed Grade				Units
			1.0V			0.9V	
			-3	-2/-2L	-1	-2L	
I_{CCINTQ}	Quiescent V_{CCINT} supply current	XC7K70T	241	241	241	187	mA
		XC7K160T	474	474	474	368	mA
		XC7K325T	810	810	810	629	mA
		XC7K355T	993	993	993	771	mA
		XC7K410T	1080	1080	1080	838	mA
		XC7K420T	1313	1313	1313	1019	mA
		XC7K480T	1313	1313	1313	1019	mA
I_{CCOQ}	Quiescent V_{CCO} supply current	XC7K70T	1	1	1	1	mA
		XC7K160T	1	1	1	1	mA
		XC7K325T	1	1	1	1	mA
		XC7K355T	1	1	1	1	mA
		XC7K410T	1	1	1	1	mA
		XC7K420T	1	1	1	1	mA
		XC7K480T	1	1	1	1	mA
I_{CCAUXQ}	Quiescent V_{CCAUX} supply current	XC7K70T	21	21	21	21	mA
		XC7K160T	40	40	40	40	mA
		XC7K325T	68	68	68	68	mA
		XC7K355T	75	75	75	75	mA
		XC7K410T	85	85	85	85	mA
		XC7K420T	99	99	99	99	mA
		XC7K480T	99	99	99	99	mA
$I_{CCAUX_{IO}Q}$	Quiescent $V_{CCAUX_{IO}}$ supply current	XC7K70T	N/A	N/A	N/A	N/A	mA
		XC7K160T	2	2	2	2	mA
		XC7K325T	2	2	2	2	mA
		XC7K355T	N/A	N/A	N/A	N/A	mA
		XC7K410T	2	2	2	2	mA
		XC7K420T	N/A	N/A	N/A	N/A	mA
		XC7K480T	N/A	N/A	N/A	N/A	mA

Table 6: Typical Quiescent Supply Current (Cont'd)

Symbol	Description	Device	Speed Grade				Units
			1.0V			0.9V	
			-3	-2/-2L	-1	-2L	
I _{CCBRAMQ}	Quiescent V _{CCBRAM} supply current	XC7K70T	6	6	6	6	mA
		XC7K160T	14	14	14	14	mA
		XC7K325T	19	19	19	19	mA
		XC7K355T	31	31	31	31	mA
		XC7K410T	34	34	34	34	mA
		XC7K420T	41	41	41	41	mA
		XC7K480T	41	41	41	41	mA

Notes:

- Typical values are specified at nominal voltage, 85°C junction temperatures (T_j) with single-ended SelectIO resources.
- Typical values are for blank configured devices with no output current loads, no active input pull-up resistors, all I/O pins are 3-state and floating.
- Use the XPower™ Estimator (XPE) spreadsheet tool (download at <http://www.xilinx.com/power>) to calculate static power consumption for conditions other than those specified.

Power-On/Off Power Supply Sequencing

The recommended power-on sequence is V_{CCINT}, V_{CCBRAM}, V_{CCAUX}, V_{CCAUX_IO}, and V_{CCO} to achieve minimum current draw and ensure that the I/Os are 3-stated at power-on. The recommended power-off sequence is the reverse of the power-on sequence. If V_{CCINT} and V_{CCBRAM} have the same recommended voltage levels then both can be powered by the same supply and ramped simultaneously. If V_{CCAUX}, V_{CCAUX_IO}, and V_{CCO} have the same recommended voltage levels then they can be powered by the same supply and ramped simultaneously.

For V_{CCO} voltages of 3.3V in HR I/O banks and configuration bank 0:

- The voltage difference between V_{CCO} and V_{CCAUX} must not exceed 2.625V for longer than T_{VCCO2VCCAUX} for each power-on/off cycle to maintain device reliability levels.
- The T_{VCCO2VCCAUX} time can be allocated in any percentage between the power-on and power-off ramps.

The recommended power-on sequence to achieve minimum current draw for the GTX transceivers is V_{CCINT}, V_{MGTAVCC}, V_{MGTAVTT} OR V_{MGTAVCC}, V_{CCINT}, V_{MGTAVTT}. There is no recommended sequencing for V_{MGTVCCAUX}. Both V_{MGTAVCC} and V_{CCINT} can be ramped simultaneously. The recommended power-off sequence is the reverse of the power-on sequence to achieve minimum current draw.

If these recommended sequences are not met, current drawn from V_{MGTAVTT} can be higher than specifications during power-up and power-down.

- When V_{MGTAVTT} is powered before V_{MGTAVCC} and V_{MGTAVTT} - V_{MGTAVCC} > 150 mV and V_{MGTAVCC} < 0.7V, the V_{MGTAVTT} current draw can increase by 460 mA per transceiver during V_{MGTAVCC} ramp up. The duration of the current draw can be up to 0.3 x T_{MGTAVCC} (ramp time from GND to 90% of V_{MGTAVCC}). The reverse is true for power-down.
- When V_{MGTAVTT} is powered before V_{CCINT} and V_{MGTAVTT} - V_{CCINT} > 150 mV and V_{CCINT} < 0.7V, the V_{MGTAVTT} current draw can increase by 50 mA per transceiver during V_{CCINT} ramp up. The duration of the current draw can be up to 0.3 x T_{VCCINT} (ramp time from GND to 90% of V_{CCINT}). The reverse is true for power-down.

DC Input and Output Levels

Values for V_{IL} and V_{IH} are recommended input voltages. Values for I_{OL} and I_{OH} are guaranteed over the recommended operating conditions at the V_{OL} and V_{OH} test points. Only selected standards are tested. These are chosen to ensure that all standards meet their specifications. The selected standards are tested at a minimum V_{CCO} with the respective V_{OL} and V_{OH} voltage levels shown. Other standards are sample tested.

Table 9: SelectIO DC Input and Output Levels (1)(2)

I/O Standard	V_{IL}		V_{IH}		V_{OL}	V_{OH}	I_{OL}	I_{OH}
	V, Min	V, Max	V, Min	V, Max	V, Max	V, Min	mA	mA
HSTL_I	-0.300	$V_{REF} - 0.100$	$V_{REF} + 0.100$	$V_{CCO} + 0.300$	0.400	$V_{CCO} - 0.400$	8	-8
HSTL_I_12	-0.300	$V_{REF} - 0.080$	$V_{REF} + 0.080$	$V_{CCO} + 0.300$	25% V_{CCO}	75% V_{CCO}	6.3	-6.3
HSTL_I_18	-0.300	$V_{REF} - 0.100$	$V_{REF} + 0.100$	$V_{CCO} + 0.300$	0.400	$V_{CCO} - 0.400$	8	-8
HSTL_II	-0.300	$V_{REF} - 0.100$	$V_{REF} + 0.100$	$V_{CCO} + 0.300$	0.400	$V_{CCO} - 0.400$	16	-16
HSTL_II_18	-0.300	$V_{REF} - 0.100$	$V_{REF} + 0.100$	$V_{CCO} + 0.300$	0.400	$V_{CCO} - 0.400$	16	-16
HSUL_12	-0.300	$V_{REF} - 0.130$	$V_{REF} + 0.130$	$V_{CCO} + 0.300$	20% V_{CCO}	80% V_{CCO}	0.1	-0.1
LVC MOS12	-0.300	35% V_{CCO}	65% V_{CCO}	$V_{CCO} + 0.300$	0.400	$V_{CCO} - 0.400$	Note 3	Note 3
LVC MOS15, LVDCI_15	-0.300	35% V_{CCO}	65% V_{CCO}	$V_{CCO} + 0.300$	25% V_{CCO}	75% V_{CCO}	Note 4	Note 4
LVC MOS18, LVDCI_18	-0.300	35% V_{CCO}	65% V_{CCO}	$V_{CCO} + 0.300$	0.450	$V_{CCO} - 0.450$	Note 5	Note 5
LVC MOS25	-0.300	0.700	1.700	$V_{CCO} + 0.300$	0.400	$V_{CCO} - 0.400$	Note 6	Note 6
LVC MOS33	-0.300	0.800	2.000	3.450	0.400	$V_{CCO} - 0.400$	Note 6	Note 6
LV TTL	-0.300	0.800	2.000	3.450	0.400	2.400	Note 7	Note 7
MOBILE_DDR	-0.300	20% V_{CCO}	80% V_{CCO}	$V_{CCO} + 0.300$	10% V_{CCO}	90% V_{CCO}	0.1	-0.1
PCI33_3	-0.500	30% V_{CCO}	50% V_{CCO}	$V_{CCO} + 0.500$	10% V_{CCO}	90% V_{CCO}	1.5	-0.5
SSTL12	-0.300	$V_{REF} - 0.100$	$V_{REF} + 0.100$	$V_{CCO} + 0.300$	$V_{CCO}/2 - 0.150$	$V_{CCO}/2 + 0.150$	14.25	-14.25
SSTL135	-0.300	$V_{REF} - 0.090$	$V_{REF} + 0.090$	$V_{CCO} + 0.300$	$V_{CCO}/2 - 0.150$	$V_{CCO}/2 + 0.150$	13.0	-13.0
SSTL135_R	-0.300	$V_{REF} - 0.090$	$V_{REF} + 0.090$	$V_{CCO} + 0.300$	$V_{CCO}/2 - 0.150$	$V_{CCO}/2 + 0.150$	8.9	-8.9
SSTL15	-0.300	$V_{REF} - 0.100$	$V_{REF} + 0.100$	$V_{CCO} + 0.300$	$V_{CCO}/2 - 0.175$	$V_{CCO}/2 + 0.175$	13.0	-13.0
SSTL15_R	-0.300	$V_{REF} - 0.100$	$V_{REF} + 0.100$	$V_{CCO} + 0.300$	$V_{CCO}/2 - 0.175$	$V_{CCO}/2 + 0.175$	8.9	-8.9
SSTL18_I	-0.300	$V_{REF} - 0.125$	$V_{REF} + 0.125$	$V_{CCO} + 0.300$	$V_{CCO}/2 - 0.470$	$V_{CCO}/2 + 0.470$	8	-8
SSTL18_II	-0.300	$V_{REF} - 0.125$	$V_{REF} + 0.125$	$V_{CCO} + 0.300$	$V_{CCO}/2 - 0.600$	$V_{CCO}/2 + 0.600$	13.4	-13.4

Notes:

1. Tested according to relevant specifications.
2. 3.3V and 2.5V standards are only supported in 3.3V I/O banks.
3. Supported drive strengths of 2, 4, 6, or 8 mA in HP I/O banks and 4, 8, or 12 mA in HR I/O banks.
4. Supported drive strengths of 2, 4, 6, 8, 12, or 16 mA in HP I/O banks and 4, 8, 12, or 16 mA in HR I/O banks.
5. Supported drive strengths of 2, 4, 6, 8, 12, or 16 mA in HP I/O banks and 4, 8, 12, 16, or 24 mA in HR I/O banks.
6. Supported drive strengths of 4, 8, 12, or 16 mA
7. Supported drive strengths of 4, 8, 12, 16, or 24 mA
8. For detailed interface specific DC voltage levels, see [UG471: 7 Series FPGAs SelectIO Resources User Guide](#).

Table 10: Differential SelectIO DC Input and Output Levels

I/O Standard	$V_{ICM}^{(1)}$			$V_{ID}^{(2)}$			$V_{OCM}^{(3)}$			$V_{OD}^{(4)}$		
	V, Min	V, Typ	V, Max	V, Min	V, Typ	V, Max	V, Min	V, Typ	V, Max	V, Min	V, Typ	V, Max
BLVDS_25	0.300	1.200	1.425	0.100	—	—	—	1.250	—	Note 5		
MINI_LVDS_25	0.300	1.200	V_{CCAUX}	0.200	0.400	0.600	1.000	1.200	1.400	0.300	0.450	0.600
PPDS_25	0.200	0.900	V_{CCAUX}	0.100	0.250	0.400	0.500	0.950	1.400	0.100	0.250	0.400
RSDS_25	0.300	0.900	1.500	0.100	0.350	0.600	1.000	1.200	1.400	0.100	0.350	0.600
TMDS_33	2.700	2.965	3.230	0.150	0.675	1.200	$V_{CCO}-0.405$	$V_{CCO}-0.300$	$V_{CCO}-0.190$	0.400	0.600	0.800

Notes:

- V_{ICM} is the input common mode voltage.
- V_{ID} is the input differential voltage ($Q - \bar{Q}$).
- V_{OCM} is the output common mode voltage.
- V_{OD} is the output differential voltage ($Q - \bar{Q}$).
- V_{OD} for BLVDS will vary significantly depending on topology and loading.
- LVDS_25 is specified in Table 12.
- LVDS is specified in Table 13.

Table 11: Complementary Differential SelectIO DC Input and Output Levels

I/O Standard	$V_{ICM}^{(1)}$			$V_{ID}^{(2)}$		$V_{OL}^{(3)}$	$V_{OH}^{(4)}$	I_{OL}	I_{OH}
	V, Min	V, Typ	V, Max	V, Min	V, Max	V, Max	V, Min	mA, Max	mA, Min
DIFF_HSTL_I	0.300	0.750	1.125	0.100	—	0.400	$V_{CCO}-0.400$	8.00	–8.00
DIFF_HSTL_I_18	0.300	0.900	1.425	0.100	—	0.400	$V_{CCO}-0.400$	8.00	–8.00
DIFF_HSTL_II	0.300	0.750	1.125	0.100	—	0.400	$V_{CCO}-0.400$	16.00	–16.00
DIFF_HSTL_II_18	0.300	0.900	1.425	0.100	—	0.400	$V_{CCO}-0.400$	16.00	–16.00
DIFF_HSUL_12	0.300	0.600	0.850	0.100	—	20% V_{CCO}	80% V_{CCO}	0.100	–0.100
DIFF_MOBILE_DDR	0.300	0.900	1.425	0.100	—	10% V_{CCO}	90% V_{CCO}	0.100	–0.100
DIFF_SSTL12	0.300	0.600	0.850	0.100	—	$(V_{CCO}/2) - 0.150$	$(V_{CCO}/2) + 0.150$	14.25	–14.25
DIFF_SSTL135	0.300	0.675	1.000	0.100	—	$(V_{CCO}/2) - 0.150$	$(V_{CCO}/2) + 0.150$	13.0	–13.0
DIFF_SSTL135_R	0.300	0.675	1.000	0.100	—	$(V_{CCO}/2) - 0.150$	$(V_{CCO}/2) + 0.150$	8.9	–8.9
DIFF_SSTL15	0.300	0.750	1.125	0.100	—	$(V_{CCO}/2) - 0.175$	$(V_{CCO}/2) + 0.175$	13.0	–13.0
DIFF_SSTL15_R	0.300	0.750	1.125	0.100	—	$(V_{CCO}/2) - 0.175$	$(V_{CCO}/2) + 0.175$	8.9	–8.9
DIFF_SSTL18_I	0.300	0.900	1.425	0.100	—	$(V_{CCO}/2) - 0.470$	$(V_{CCO}/2) + 0.470$	8.00	–8.00
DIFF_SSTL18_II	0.300	0.900	1.425	0.100	—	$(V_{CCO}/2) - 0.600$	$(V_{CCO}/2) + 0.600$	13.4	–13.4

Notes:

- V_{ICM} is the input common mode voltage.
- V_{ID} is the input differential voltage ($Q - \bar{Q}$).
- V_{OL} is the single-ended low-output voltage.
- V_{OH} is the single-ended high-output voltage.

LVDS DC Specifications (LVDS_25)

The LVDS_25 standard is available in the HR I/O banks. See [UG471: 7 Series FPGAs SelectIO Resources User Guide](#) for more information.

Table 12: LVDS_25 DC Specifications

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
V_{CCO}	Supply Voltage		2.375	2.500	2.625	V
V_{OH}	Output High Voltage for Q and $\overline{Q}$	$R_T = 100\ \Omega$ across Q and $\overline{Q}$ signals	–	–	1.675	V
V_{OL}	Output Low Voltage for Q and $\overline{Q}$	$R_T = 100\ \Omega$ across Q and $\overline{Q}$ signals	0.700	–	–	V
V_{ODIFF}	Differential Output Voltage (Q – $\overline{Q}$), Q = High ($\overline{Q}$ – Q), $\overline{Q}$ = High	$R_T = 100\ \Omega$ across Q and $\overline{Q}$ signals	247	350	600	mV
V_{OCM}	Output Common-Mode Voltage	$R_T = 100\ \Omega$ across Q and $\overline{Q}$ signals	1.000	1.250	1.425	V
V_{IDIFF}	Differential Input Voltage (Q – $\overline{Q}$), Q = High ($\overline{Q}$ – Q), $\overline{Q}$ = High		100	350	600	mV
V_{ICM}	Input Common-Mode Voltage		0.300	1.200	1.425	V

LVDS DC Specifications (LVDS)

The LVDS standard is available in the HP I/O banks. See [UG471: 7 Series FPGAs SelectIO Resources User Guide](#) for more information.

Table 13: LVDS DC Specifications

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
V_{CCO}	Supply Voltage		1.710	1.800	1.890	V
V_{OH}	Output High Voltage for Q and $\overline{Q}$	$R_T = 100\ \Omega$ across Q and $\overline{Q}$ signals	–	–	1.675	V
V_{OL}	Output Low Voltage for Q and $\overline{Q}$	$R_T = 100\ \Omega$ across Q and $\overline{Q}$ signals	0.825	–	–	V
V_{ODIFF}	Differential Output Voltage (Q – $\overline{Q}$), Q = High ($\overline{Q}$ – Q), $\overline{Q}$ = High	$R_T = 100\ \Omega$ across Q and $\overline{Q}$ signals	247	350	600	mV
V_{OCM}	Output Common-Mode Voltage	$R_T = 100\ \Omega$ across Q and $\overline{Q}$ signals	1.000	1.250	1.425	V
V_{IDIFF}	Differential Input Voltage (Q – $\overline{Q}$), Q = High ($\overline{Q}$ – Q), $\overline{Q}$ = High	Common-mode input voltage = 1.25V	100	350	600	mV
V_{ICM}	Input Common-Mode Voltage	Differential input voltage = ± 350 mV	0.300	1.200	1.425	V

Table 17: Maximum Physical Interface (PHY) Rate for Memory Interfaces (FFG Packages)⁽¹⁾⁽²⁾

Memory Standard	I/O Bank Type	V _{CCAUX_IO}	Speed Grade				Units
			1.0V			0.9V	
			-3	-2/-2L	-1	-2L	
4:1 Memory Controllers							
DDR3	HP	2.0V	1866	1866	1600	1333	Mb/s
	HP	1.8V	1600	1333	1066	1066	Mb/s
	HR	N/A	1066	1066	800	800	Mb/s
DDR3L	HP	2.0V	1600	1600	1333	1066	Mb/s
	HP	1.8V	1333	1066	800	800	Mb/s
	HR	N/A	800	800	667	667	Mb/s
DDR2	HP	2.0V	800	800	800	800	Mb/s
	HP	1.8V	800	800	800	800	Mb/s
	HR	N/A	800	800	800	800	Mb/s
RLDRAM III ⁽³⁾	HP	2.0V	800	667	667	533	MHz
	HP	1.8V	550	500	450	450	MHz
	HR	N/A	N/A				
2:1 Memory Controllers							
DDR3	HP	2.0V	1066	1066	800	800	Mb/s
	HP	1.8V	1066	1066	800	800	Mb/s
	HR	N/A	1066	1066	800	800	Mb/s
DDR3L	HP	2.0V	1066	1066	800	800	Mb/s
	HP	1.8V	1066	1066	800	800	Mb/s
	HR	N/A	800	800	667	667	Mb/s
DDR2	HP	2.0V	800	800	800	800	Mb/s
	HP	1.8V					
	HR	N/A					
QDR II+ ⁽⁴⁾	HP	2.0V	550	500	450	450	MHz
	HP	1.8V					
	HR	N/A					
RLDRAM II	HP	2.0V	533	500	450	450	MHz
	HP	1.8V					
	HR	N/A					
LPDDR2 ⁽³⁾	HP	2.0V	800	800	800	800	Mb/s
	HP	1.8V	800	800	800	800	Mb/s
	HR	N/A	800	667	667	667	Mb/s

Notes:

1. V_{REF} tracking is required. For more information, see [UG586](#), 7 Series FPGAs Memory Interface Solutions User Guide.
2. When using the internal V_{REF} the maximum data rate is 800 Mb/s (400 MHz).
3. RLDRAM III (BL = 4, BL = 8) and LPDDR2 specifications have not been validated with memory IP.
4. The maximum QDRII+ performance specifications are for burst-length 4 (BL = 4) implementations. Burst length 2 (BL = 2) implementations are limited to 333 MHz for all speed grades and I/O bank types.

Table 19: 3.3V IOB High Range (HR) Switching Characteristics (Cont'd)

I/O Standard	T _{IOPi}				T _{IOPp}				T _{IOTp}				Units
	Speed Grade				Speed Grade				Speed Grade				
	1.0V			0.9V	1.0V			0.9V	1.0V			0.9V	
	-3	-2/-2L	-1	-2L	-3	-2/-2L	-1	-2L	-3	-2/-2L	-1	-2L	
LVC MOS15_S16	0.66	0.69	0.81	0.90	1.76	1.95	2.13	1.91	2.52	2.81	3.12	2.42	ns
LVC MOS15_F4	0.66	0.69	0.81	0.90	3.39	3.60	3.80	1.98	4.15	4.46	4.79	2.50	ns
LVC MOS15_F8	0.66	0.69	0.81	0.90	1.79	1.99	2.18	1.92	2.55	2.85	3.17	2.44	ns
LVC MOS15_F12	0.66	0.69	0.81	0.90	1.40	1.54	1.65	1.67	2.16	2.40	2.64	2.19	ns
LVC MOS15_F16	0.66	0.69	0.81	0.90	1.37	1.51	1.61	1.66	2.13	2.37	2.60	2.17	ns
LVC MOS12_S4	0.88	0.91	1.00	1.01	3.85	4.22	4.69	2.89	4.61	5.08	5.68	3.41	ns
LVC MOS12_S8	0.88	0.91	1.00	1.01	2.52	2.96	3.52	2.41	3.28	3.82	4.51	2.92	ns
LVC MOS12_S12 ⁽¹⁾	0.88	0.91	1.00	1.01	2.06	2.31	2.59	2.11	2.82	3.17	3.58	2.63	ns
LVC MOS12_F4	0.88	0.91	1.00	1.01	3.44	3.73	4.06	2.30	4.20	4.59	5.05	2.81	ns
LVC MOS12_F8	0.88	0.91	1.00	1.01	1.72	2.04	2.40	1.86	2.48	2.90	3.39	2.38	ns
LVC MOS12_F12 ⁽¹⁾	0.88	0.91	1.00	1.01	1.54	1.71	1.87	1.69	2.30	2.57	2.86	2.20	ns
SSTL135_S	0.61	0.64	0.73	0.79	1.27	1.40	1.50	1.64	2.03	2.26	2.49	2.16	ns
SSTL15_S	0.61	0.64	0.73	0.73	1.24	1.37	1.47	1.59	2.00	2.23	2.46	2.11	ns
SSTL18_I_S	0.64	0.67	0.76	0.79	1.59	1.74	1.85	1.95	2.35	2.60	2.84	2.47	ns
SSTL18_II_S	0.64	0.67	0.76	0.78	1.27	1.40	1.50	1.63	2.03	2.26	2.49	2.14	ns
DIFF_SSTL135_S	0.59	0.61	0.73	0.79	1.27	1.40	1.50	1.64	2.03	2.26	2.49	2.16	ns
DIFF_SSTL15_S	0.63	0.67	0.77	0.79	1.24	1.37	1.47	1.59	2.00	2.23	2.46	2.11	ns
DIFF_SSTL18_I_S	0.65	0.69	0.78	0.79	1.50	1.63	1.72	1.95	2.26	2.49	2.71	2.47	ns
DIFF_SSTL18_II_S	0.65	0.69	0.78	0.79	1.13	1.22	1.25	1.66	1.89	2.08	2.24	2.17	ns
SSTL135_F	0.61	0.64	0.73	0.79	1.04	1.17	1.26	1.42	1.80	2.03	2.25	1.94	ns
SSTL15_F	0.61	0.64	0.73	0.73	1.04	1.17	1.26	1.39	1.80	2.03	2.25	1.91	ns
SSTL18_I_F	0.64	0.67	0.76	0.79	1.12	1.22	1.26	1.44	1.88	2.08	2.25	1.95	ns
SSTL18_II_F	0.64	0.67	0.76	0.78	1.05	1.18	1.28	1.42	1.81	2.04	2.27	1.94	ns
DIFF_SSTL135_F	0.59	0.61	0.73	0.79	1.04	1.17	1.26	1.42	1.80	2.03	2.25	1.94	ns
DIFF_SSTL15_F	0.63	0.67	0.77	0.79	1.04	1.17	1.26	1.39	1.80	2.03	2.25	1.91	ns
DIFF_SSTL18_I_F	0.65	0.69	0.78	0.79	1.10	1.19	1.23	1.52	1.86	2.05	2.22	2.03	ns
DIFF_SSTL18_II_F	0.65	0.69	0.78	0.79	1.02	1.10	1.14	1.50	1.78	1.96	2.13	2.02	ns

Notes:

1. This I/O standard is only available in the 3.3V high-range (HR) banks.

Output Serializer/Deserializer Switching Characteristics

Table 25: OSERDES Switching Characteristics

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
Setup/Hold						
T _{OSDCK_D} /T _{OSCKD_D}	D input Setup/Hold with respect to CLKDIV	0.37/0.02	0.40/0.02	0.55/0.02	0.44/−0.24	ns
T _{OSDCK_T} /T _{OSCKD_T} ⁽¹⁾	T input Setup/Hold with respect to CLK	0.49/−0.15	0.56/−0.15	0.68/−0.15	0.67/−0.25	ns
T _{OSDCK_T2} /T _{OSCKD_T2} ⁽¹⁾	T input Setup/Hold with respect to CLKDIV	0.27/−0.15	0.30/−0.15	0.34/−0.15	0.46/−0.25	ns
T _{OSCCK_OCE} /T _{OSCKC_OCE}	OCE input Setup/Hold with respect to CLK	0.28/0.03	0.29/0.03	0.45/0.03	0.35/−0.15	ns
T _{OSCCK_S}	SR (Reset) input Setup with respect to CLKDIV	0.41	0.46	0.75	0.70	ns
T _{OSCCK_TCE} /T _{OSCKC_TCE}	TCE input Setup/Hold with respect to CLK	0.28/0.01	0.30/0.01	0.45/0.01	0.31/−0.15	ns
Sequential Delays						
T _{OSCKO_OQ}	Clock to out from CLK to OQ	0.35	0.37	0.42	0.54	ns
T _{OSCKO_TQ}	Clock to out from CLK to TQ	0.41	0.43	0.49	0.63	ns
Combinatorial						
T _{OSDO_TTQ}	T input to TQ Out	0.73	0.81	0.97	1.18	ns

Notes:

- T_{OSDCK_T2} and T_{OSCKD_T2} are reported as T_{OSDCK_T}/T_{OSCKD_T} in TRACE report.

Table 27: IO_FIFO Switching Characteristics

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
IO_FIFO Clock to Out Delays						
T _{OFFCKO_DO}	RDCLK to Q outputs	0.51	0.56	0.63	0.81	ns
T _{CKO_FLAGS}	Clock to IO_FIFO Flags	0.59	0.62	0.81	0.77	ns
Setup/Hold						
T _{CCK_D} /T _{CKC_D}	D inputs to WRCLK	0.43/−0.01	0.47/−0.01	0.53/−0.01	0.76/−0.05	ns
T _{IFFCKC_WREN} /T _{IFFCKC_WREN}	WREN to WRCLK	0.39/−0.01	0.43/−0.01	0.50/−0.01	0.70/−0.05	ns
T _{OFFCKC_RDEN} /T _{OFFCKC_RDEN}	RDEN to RDCLK	0.49/0.01	0.53/0.02	0.61/0.02	0.79/−0.02	ns
Minimum Pulse Width						
T _{PWH_IO_FIFO}	RESET, RDCLK, WRCLK	0.81	0.92	1.08	1.29	ns
T _{PWL_IO_FIFO}	RESET, RDCLK, WRCLK	0.81	0.92	1.08	1.29	ns
Maximum Frequency						
F _{MAX}	RDCLK and WRCLK	533.05	470.37	400.00	333.33	MHz

CLB Distributed RAM Switching Characteristics (SLICEM Only)

Table 29: CLB Distributed RAM Switching Characteristics

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
Sequential Delays						
T _{SHCKO}	Clock to A – B outputs	0.68	0.70	0.85	1.08	ns, Max
T _{SHCKO_1}	Clock to AMUX – BMUX outputs	0.91	0.95	1.15	1.44	ns, Max
Setup and Hold Times Before/After Clock CLK						
T _{DS_LRAM} /T _{DH_LRAM}	A – D inputs to CLK	0.45/0.23	0.45/0.24	0.54/0.27	0.69/0.33	ns, Min
T _{AS_LRAM} /T _{AH_LRAM}	Address An inputs to clock	0.13/0.50	0.14/0.50	0.17/0.58	0.21/0.63	ns, Min
	Address An inputs through MUXs and/or carry logic to clock	0.40/0.16	0.42/0.17	0.52/0.23	0.63/0.23	ns, Min
T _{WS_LRAM} /T _{WH_LRAM}	WE input to clock	0.29/0.09	0.30/0.09	0.36/0.09	0.46/0.10	ns, Min
T _{CECK_LRAM} / T _{CKCE_LRAM}	CE input to CLK	0.29/0.09	0.30/0.09	0.37/0.09	0.47/0.10	ns, Min
Clock CLK						
T _{MPW}	Minimum pulse width	0.68	0.77	0.91	1.11	ns, Min
T _{MCP}	Minimum clock period	1.35	1.54	1.82	2.22	ns, Min

Notes:

1. A Zero "0" Hold Time listing indicates no hold time or a negative hold time.
2. T_{SHCKO} also represents the CLK to XMUX output. Refer to TRACE report for the CLK to XMUX path.

CLB Shift Register Switching Characteristics (SLICEM Only)

Table 30: CLB Shift Register Switching Characteristics

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
Sequential Delays						
T _{REG}	Clock to A – D outputs	0.96	0.98	1.20	1.35	ns, Max
T _{REG_MUX}	Clock to AMUX – DMUX output	1.19	1.23	1.50	1.72	ns, Max
T _{REG_M31}	Clock to DMUX output via M31 output	0.89	0.91	1.10	1.25	ns, Max
Setup and Hold Times Before/After Clock CLK						
T _{WS_SHFREG} / T _{WH_SHFREG}	WE input	0.26/0.09	0.27/0.09	0.33/0.09	0.41/0.10	ns, Min
T _{CECK_SHFREG} / T _{CKCE_SHFREG}	CE input to CLK	0.27/0.09	0.28/0.09	0.33/0.09	0.42/0.10	ns, Min
T _{DS_SHFREG} / T _{DH_SHFREG}	A – D inputs to CLK	0.28/0.26	0.28/0.26	0.33/0.30	0.41/0.36	ns, Min
Clock CLK						
T _{MPW_SHFREG}	Minimum pulse width	0.55	0.65	0.78	0.91	ns, Min

Notes:

1. A Zero "0" Hold Time listing indicates no hold time or a negative hold time.

Block RAM and FIFO Switching Characteristics

Table 31: Block RAM and FIFO Switching Characteristics

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
Block RAM and FIFO Clock-to-Out Delays						
T_{RCKO_DO} and $T_{RCKO_DO_REG}^{(1)}$	Clock CLK to DOUT output (without output register) ⁽²⁾⁽³⁾	1.57	1.80	2.08	2.44	ns, Max
	Clock CLK to DOUT output (with output register) ⁽⁴⁾⁽⁵⁾	0.54	0.63	0.75	0.86	ns, Max
$T_{RCKO_DO_ECC}$ and $T_{RCKO_DO_ECC_REG}$	Clock CLK to DOUT output with ECC (without output register) ⁽²⁾⁽³⁾	2.35	2.58	3.26	4.49	ns, Max
	Clock CLK to DOUT output with ECC (with output register) ⁽⁴⁾⁽⁵⁾	0.62	0.69	0.80	0.94	ns, Max
$T_{RCKO_DO_CASCOUT}$ and $T_{RCKO_DO_CASCOUT_REG}$	Clock CLK to DOUT output with Cascade (without output register) ⁽²⁾	2.21	2.45	2.80	3.19	ns, Max
	Clock CLK to DOUT output with Cascade (with output register) ⁽⁴⁾	0.98	1.08	1.24	1.32	ns, Max
T_{RCKO_FLAGS}	Clock CLK to FIFO flags outputs ⁽⁶⁾	0.65	0.74	0.89	0.97	ns, Max
$T_{RCKO_POINTERS}$	Clock CLK to FIFO pointers outputs ⁽⁷⁾	0.79	0.87	0.98	1.10	ns, Max
$T_{RCKO_PARITY_ECC}$	Clock CLK to ECCPARITY in ECC encode only mode	0.66	0.72	0.80	0.93	ns, Max
$T_{RCKO_SDBIT_ECC}$ and $T_{RCKO_SDBIT_ECC_REG}$	Clock CLK to BITERR (without output register)	2.17	2.38	3.01	4.15	ns, Max
	Clock CLK to BITERR (with output register)	0.57	0.65	0.76	0.89	ns, Max
$T_{RCKO_RDADDR_ECC}$ and $T_{RCKO_RDADDR_ECC_REG}$	Clock CLK to RDADDR output with ECC (without output register)	0.64	0.74	0.90	0.98	ns, Max
	Clock CLK to RDADDR output with ECC (with output register)	0.71	0.79	0.92	1.10	ns, Max
Setup and Hold Times Before/After Clock CLK						
$T_{RCKCK_ADDR}/T_{RCKC_ADDR}$	ADDR inputs ⁽⁸⁾	0.38/0.27	0.42/0.28	0.48/0.31	0.65/0.38	ns, Min
$T_{RDCK_DI_WF_NC}/T_{RCKD_DI_WF_NC}$	Data input setup/hold time when block RAM is configured in WRITE_FIRST or NO_CHANGE mode ⁽⁹⁾	0.49/0.51	0.55/0.53	0.63/0.57	0.78/0.64	ns, Min
$T_{RDCK_DI_RF}/T_{RCKD_DI_RF}$	Data input setup/hold time when block RAM is configured in READ_FIRST mode ⁽⁹⁾	0.17/0.25	0.19/0.29	0.21/0.35	0.25/0.32	ns, Min
$T_{RDCK_DI_ECC}/T_{RCKD_DI_ECC}$	DIN inputs with block RAM ECC in standard mode ⁽⁹⁾	0.42/0.37	0.47/0.39	0.53/0.43	0.66/0.46	ns, Min
$T_{RDCK_DI_ECCW}/T_{RCKD_DI_ECCW}$	DIN inputs with block RAM ECC encode only ⁽⁹⁾	0.79/0.37	0.87/0.39	0.99/0.43	1.17/0.41	ns, Min
$T_{RDCK_DI_ECC_FIFO}/T_{RCKD_DI_ECC_FIFO}$	DIN inputs with FIFO ECC in standard mode ⁽⁹⁾	0.89/0.47	0.98/0.50	1.12/0.54	1.32/0.65	ns, Min
$T_{RCKCK_INJECTBITERR}/T_{RCKC_INJECTBITERR}$	Inject single/double bit error in ECC mode	0.49/0.30	0.55/0.31	0.63/0.34	0.78/0.41	ns, Min
T_{RCKCK_EN}/T_{RCKC_EN}	Block RAM Enable (EN) input	0.30/0.17	0.33/0.18	0.38/0.20	0.48/0.22	ns, Min
$T_{RCKCK_REGCE}/T_{RCKC_REGCE}$	CE input of output register	0.21/0.13	0.25/0.13	0.31/0.14	0.34/0.16	ns, Min
$T_{RCKCK_RSTREG}/T_{RCKC_RSTREG}$	Synchronous RSTREG input	0.25/0.06	0.27/0.06	0.29/0.06	0.35/0.06	ns, Min

Table 32: DSP48E1 Switching Characteristics (Cont'd)

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
Setup and Hold Times of the RST Pins						
$T_{\text{DSPDCK}_{\{\text{RSTA}; \text{RSTB}\}}_{\{\text{AREG}; \text{BREG}\}}/T_{\text{DSPCKD}_{\{\text{RSTA}; \text{RSTB}\}}_{\{\text{AREG}; \text{BREG}\}}}$	{RSTA, RSTB} input to {A, B} register CLK	0.34/ 0.10	0.39/ 0.11	0.47/ 0.13	0.53/ 0.34	ns
$T_{\text{DSPDCK_RSTC_CREG}}/T_{\text{DSPCKD_RSTC_CREG}}$	RSTC input to C register CLK	0.06/ 0.22	0.07/ 0.24	0.08/ 0.26	0.08/ 0.31	ns
$T_{\text{DSPDCK_RSTD_DREG}}/T_{\text{DSPCKD_RSTD_DREG}}$	RSTD input to D register CLK	0.37/ 0.06	0.42/ 0.06	0.50/ 0.07	0.57/ 0.07	ns
$T_{\text{DSPDCK_RSTM_MREG}}/T_{\text{DSPCKD_RSTM_MREG}}$	RSTM input to M register CLK	0.18/ 0.18	0.20/ 0.21	0.23/ 0.24	0.24/ 0.29	ns
$T_{\text{DSPDCK_RSTP_PREG}}/T_{\text{DSPCKD_RSTP_PREG}}$	RSTP input to P register CLK	0.24/ 0.01	0.26/ 0.01	0.30/ 0.01	0.37/ 0.00	ns
Combinatorial Delays from Input Pins to Output Pins						
$T_{\text{DSPDO_A_CARRYOUT_MULT}}$	A input to CARRYOUT output using multiplier	3.21	3.69	4.39	5.60	ns
$T_{\text{DSPDO_D_P_MULT}}$	D input to P output using multiplier	3.15	3.61	4.30	5.44	ns
$T_{\text{DSPDO_A_P}}$	A input to P output not using multiplier	1.30	1.48	1.76	2.10	ns
$T_{\text{DSPDO_C_P}}$	C input to P output	1.13	1.30	1.55	1.84	ns
Combinatorial Delays from Input Pins to Cascading Output Pins						
$T_{\text{DSPDO}_{\{\text{A}; \text{B}\}}_{\{\text{ACOUT}; \text{BCOUT}\}}}$	{A, B} input to {ACOUT, BCOUT} output	0.47	0.53	0.63	0.75	ns
$T_{\text{DSPDO}_{\{\text{A}; \text{B}\}}_{\text{CARRYCASCOUT_MULT}}}$	{A, B} input to CARRYCASCOUT output using multiplier	3.44	3.94	4.69	5.96	ns
$T_{\text{DSPDO_D_CARRYCASCOUT_MULT}}$	D input to CARRYCASCOUT output using multiplier	3.36	3.85	4.58	5.77	ns
$T_{\text{DSPDO}_{\{\text{A}; \text{B}\}}_{\text{CARRYCASCOUT}}}$	{A, B} input to CARRYCASCOUT output not using multiplier	1.50	1.72	2.04	2.44	ns
$T_{\text{DSPDO_C_CARRYCASCOUT}}$	C input to CARRYCASCOUT output	1.34	1.53	1.83	2.18	ns
Combinatorial Delays from Cascading Input Pins to All Output Pins						
$T_{\text{DSPDO_ACIN_P_MULT}}$	ACIN input to P output using multiplier	3.09	3.55	4.24	5.42	ns
$T_{\text{DSPDO_ACIN_P}}$	ACIN input to P output not using multiplier	1.16	1.33	1.59	2.07	ns
$T_{\text{DSPDO_ACIN_ACOUT}}$	ACIN input to ACOUT output	0.32	0.37	0.45	0.53	ns
$T_{\text{DSPDO_ACIN_CARRYCASCOUT_MULT}}$	ACIN input to CARRYCASCOUT output using multiplier	3.30	3.79	4.52	5.76	ns
$T_{\text{DSPDO_ACIN_CARRYCASCOUT}}$	ACIN input to CARRYCASCOUT output not using multiplier	1.37	1.57	1.87	2.40	ns
$T_{\text{DSPDO_PCIN_P}}$	PCIN input to P output	0.94	1.08	1.29	1.54	ns
$T_{\text{DSPDO_PCIN_CARRYCASCOUT}}$	PCIN input to CARRYCASCOUT output	1.15	1.32	1.57	1.88	ns
Clock to Outs from Output Register Clock to Output Pins						
$T_{\text{DSPCKO_P_PREG}}$	CLK PREG to P output	0.33	0.35	0.39	0.45	ns
$T_{\text{DSPCKO_CARRYCASCOUT_PREG}}$	CLK PREG to CARRYCASCOUT output	0.44	0.50	0.59	0.71	ns

Table 42: Clock-Capable Clock Input to Output Delay With MMCM

Symbol	Description	Device	Speed Grade				Units
			1.0V			0.9V	
			-3	-2/-2L	-1	-2L	
SSTL15 Clock-Capable Clock Input to Output Delay using Output Flip-Flop, Fast Slew Rate, <i>with</i> MMCM.							
T _{ICKOFMMCMCC}	Clock-capable clock input and OUTFF <i>with</i> MMCM	XC7K70T	0.95	0.95	0.95	1.74	ns
		XC7K160T	0.96	0.96	0.96	1.78	ns
		XC7K325T	1.00	1.00	1.00	1.82	ns
		XC7K355T	1.00	1.00	1.00	1.78	ns
		XC7K410T	1.00	1.00	1.00	1.82	ns
		XC7K420T	1.07	1.07	1.07	1.82	ns
		XC7K480T	1.07	1.07	1.07	1.82	ns

Notes:

1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. MMCM output jitter is already included in the timing calculation.

Table 43: Clock-Capable Clock Input to Output Delay With PLL

Symbol	Description	Device	Speed Grade				Units
			1.0V			0.9V	
			-3	-2/-2L	-1	-2L	
SSTL15 Clock-Capable Clock Input to Output Delay using Output Flip-Flop, Fast Slew Rate, <i>with</i> PLL.							
T _{ICKOFPLLCC}	Clock-capable clock input and OUTFF <i>with</i> PLL	XC7K70T	0.84	0.84	0.84	1.45	ns
		XC7K160T	0.89	0.89	0.89	1.54	ns
		XC7K325T	0.89	0.89	0.89	1.54	ns
		XC7K355T	0.89	0.89	0.89	1.50	ns
		XC7K410T	0.89	0.89	0.89	1.54	ns
		XC7K420T	0.96	0.96	0.96	1.54	ns
		XC7K480T	0.96	0.96	0.96	1.54	ns

Notes:

1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. PLL output jitter is already included in the timing calculation.

Table 44: Pin-to-Pin, Clock-to-Out using BUFIO

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
SSTL15 Clock-Capable Clock Input to Output Delay using Output Flip-Flop, Fast Slew Rate, <i>with</i> BUFIO.						
T _{ICKOFCS}	Clock-to-Out of I/O clock for HR I/O banks	4.93	5.52	6.20	6.97	ns
	Clock-to-Out of I/O clock for HP I/O banks	4.85	5.44	6.11	6.90	ns

Additional Package Parameter Guidelines

The parameters in this section provide the necessary values for calculating timing budgets for Kintex-7 FPGA clock transmitter and receiver data-valid windows.

Table 50: Package Skew

Symbol	Description	Device	Package	Value	Units
T _{PKGSKEW}	Package Skew ⁽¹⁾	XC7K70T	FBG484	108	ps
			FBG676	135	ps
		XC7K160T	FBG484	118	ps
			FBG676	136	ps
			FFG676	161	ps
		XC7K325T	FBG676	146	ps
			FFG676	154	ps
			FBG900	163	ps
			FFG900	161	ps
		XC7K355T	FFG901	149	ps
		XC7K410T	FBG676	165	ps
			FFG676	168	ps
			FBG900	151	ps
			FFG900	146	ps
		XC7K420T	FFG901	149	ps
			FFG1156	145	ps
		XC7K480T	FFG901	149	ps
			FFG1156	145	ps

Notes:

- These values represent the worst-case skew between any two SelectIO resources in the package: shortest delay to longest delay from die pad to ball.
- Package delay information is available for these device/package combinations. This information can be used to deskew the package.

Table 59: GTX Transceiver Receiver Switching Characteristics

Symbol	Description		Min	Typ	Max	Units
F _{GTXRX}	Serial data rate	RX oversampler not enabled	0.500	–	F _{GTXMAX}	Gb/s
T _{RXELECIDLE}	Time for RXELECIDLE to respond to loss or restoration of data		–	10	–	ns
RX _{OOBVDPP}	OOB detect threshold peak-to-peak		60	–	150	mV
RX _{SST}	Receiver spread-spectrum tracking ⁽¹⁾	Modulated @ 33 KHz	–5000	–	0	ppm
RX _{RL}	Run length (CID)		–	–	512	UI
RX _{PPMTOL}	Data/REFCLK PPM offset tolerance	Bit rates ≤ 6.6 Gb/s	–1250	–	1250	ppm
		Bit rates > 6.6 Gb/s and ≤ 8.0 Gb/s	–700	–	700	ppm
		Bit rates > 8.0 Gb/s	–200	–	200	ppm
SJ Jitter Tolerance ⁽²⁾						
JT_SJ _{12.5}	Sinusoidal Jitter (QPLL) ⁽³⁾	12.5 Gb/s	0.3	–	–	UI
JT_SJ _{11.18}	Sinusoidal Jitter (QPLL) ⁽³⁾	11.18 Gb/s	0.3	–	–	UI
JT_SJ _{10.32}	Sinusoidal Jitter (QPLL) ⁽³⁾	10.32 Gb/s	0.3	–	–	UI
JT_SJ _{9.95}	Sinusoidal Jitter (QPLL) ⁽³⁾	9.95 Gb/s	0.3	–	–	UI
JT_SJ _{9.8}	Sinusoidal Jitter (QPLL) ⁽³⁾	9.8 Gb/s	0.3	–	–	UI
JT_SJ _{8.0}	Sinusoidal Jitter (QPLL) ⁽³⁾	8.0 Gb/s	0.44	–	–	UI
JT_SJ _{6.6_QPLL}	Sinusoidal Jitter (QPLL) ⁽³⁾	6.6 Gb/s	0.48	–	–	UI
JT_SJ _{6.6_CPLL}	Sinusoidal Jitter (CPLL) ⁽³⁾	6.6 Gb/s	0.44	–	–	UI
JT_SJ _{5.0}	Sinusoidal Jitter (CPLL) ⁽³⁾	5.0 Gb/s	0.44	–	–	UI
JT_SJ _{4.25}	Sinusoidal Jitter (CPLL) ⁽³⁾	4.25 Gb/s	0.44	–	–	UI
JT_SJ _{3.75}	Sinusoidal Jitter (CPLL) ⁽³⁾	3.75 Gb/s	0.44	–	–	UI
JT_SJ _{3.2}	Sinusoidal Jitter (CPLL) ⁽³⁾	3.2 Gb/s ⁽⁴⁾	0.45	–	–	UI
JT_SJ _{3.2L}	Sinusoidal Jitter (CPLL) ⁽³⁾	3.2 Gb/s ⁽⁵⁾	0.45	–	–	UI
JT_SJ _{2.5}	Sinusoidal Jitter (CPLL) ⁽³⁾	2.5 Gb/s ⁽⁶⁾	0.5	–	–	UI
JT_SJ _{1.25}	Sinusoidal Jitter (CPLL) ⁽³⁾	1.25 Gb/s ⁽⁷⁾	0.5	–	–	UI
JT_SJ ₅₀₀	Sinusoidal Jitter (CPLL) ⁽³⁾	500 Mb/s	0.4	–	–	UI
SJ Jitter Tolerance with Stressed Eye ⁽²⁾						
JT_TJSE _{3.2}	Total Jitter with Stressed Eye ⁽⁸⁾	3.2 Gb/s	0.70	–	–	UI
JT_TJSE _{6.6}		6.6 Gb/s	0.70	–	–	UI
JT_SJSE _{3.2}	Sinusoidal Jitter with Stressed Eye ⁽⁸⁾	3.2 Gb/s	0.1	–	–	UI
JT_SJSE _{6.6}		6.6 Gb/s	0.1	–	–	UI

Notes:

- Using RXOUT_DIV = 1, 2, and 4.
- All jitter values are based on a bit error ratio of $1e^{-12}$.
- The frequency of the injected sinusoidal jitter is 10 MHz.
- CPLL frequency at 3.2 GHz and RXOUT_DIV = 2.
- CPLL frequency at 1.6 GHz and RXOUT_DIV = 1.
- CPLL frequency at 2.5 GHz and RXOUT_DIV = 2.
- CPLL frequency at 2.5 GHz and RXOUT_DIV = 4.
- Composite jitter with RX and LPM or DFE mode.

GTX Transceiver Protocol Jitter Characteristics

For Table 60 through Table 65, the [UG476: 7 Series FPGAs GTX/GTH Transceiver User Guide](#) contains recommended settings for optimal usage of protocol specific characteristics.

Table 60: Gigabit Ethernet Protocol Characteristics

Description	Line Rate (Mb/s)	Min	Max	Units
Gigabit Ethernet Transmitter Jitter Generation				
Total transmitter jitter (T _{TJ})	1250	–	0.24	UI
Gigabit Ethernet Receiver High Frequency Jitter Tolerance				
Total receiver jitter tolerance	1250	0.749	–	UI

Table 61: XAUI Protocol Characteristics

Description	Line Rate (Mb/s)	Min	Max	Units
XAUI Transmitter Jitter Generation				
Total transmitter jitter (T _{TJ})	3125	–	0.35	UI
XAUI Receiver High Frequency Jitter Tolerance				
Total receiver jitter tolerance	3125	0.65	–	UI

Table 62: PCI Express Protocol Characteristics⁽¹⁾

Standard	Description		Line Rate (Mb/s)	Min	Max	Units
PCI Express Transmitter Jitter Generation						
PCI Express Gen 1	Total transmitter jitter		2500	–	0.25	UI
PCI Express Gen 2	Total transmitter jitter		5000	–	0.25	UI
PCI Express Gen 3 ⁽²⁾	Total transmitter jitter uncorrelated		8000	–	31.25	ps
	Deterministic transmitter jitter uncorrelated			–	12	ps
PCI Express Receiver High Frequency Jitter Tolerance						
PCI Express Gen 1	Total receiver jitter tolerance		2500	0.65	–	UI
PCI Express Gen 2 ⁽³⁾	Receiver inherent timing error		5000	0.40	–	UI
	Receiver inherent deterministic timing error			0.30	–	UI
PCI Express Gen 3 ⁽²⁾	Receiver sinusoidal jitter tolerance	0.03 MHz–1.0 MHz	8000	1.00	–	UI
		1.0 MHz–10 MHz		Note 4	–	UI
		10 MHz–100 MHz		0.10	–	UI

Notes:

1. Tested per card electromechanical (CEM) methodology.
2. PCI-SIG 3.0 certification and compliance test boards are currently not available.
3. Using common REFCLK.
4. Between 1 MHz and 10 MHz the minimum sinusoidal jitter roll-off with a slope of 20dB/decade.

Table 63: CEI-6G and CEI-11G Protocol Characteristics

Description	Line Rate (Mb/s)	Interface	Min	Max	Units
CEI-6G Transmitter Jitter Generation					
Total transmitter jitter ⁽¹⁾	4976–6375	CEI-6G-SR	–	0.3	UI
		CEI-6G-LR	–	0.3	UI
CEI-6G Receiver High Frequency Jitter Tolerance					
Total receiver jitter tolerance ⁽¹⁾	4976–6375	CEI-6G-SR	0.6	–	UI
		CEI-6G-LR	0.95	–	UI
CEI-11G Transmitter Jitter Generation					
Total transmitter jitter ⁽²⁾	9950–11100	CEI-11G-SR	–	0.3	UI
		CEI-11G-LR/MR	–	0.3	UI
CEI-11G Receiver High Frequency Jitter Tolerance					
Total receiver jitter tolerance ⁽²⁾	9950–11100	CEI-11G-SR	0.65	–	UI
		CEI-11G-MR	0.65	–	UI
		CEI-11G-LR	0.825	–	UI

Notes:

1. Tested at most commonly used line rate of 6250 Mb/s using 390.625 MHz reference clock.
2. Tested at line rate of 9950 Mb/s using 155.46875 MHz reference clock and 11100 Mb/s using 173.4375 MHz reference clock.

Table 64: SFP+ Protocol Characteristics

Description	Line Rate (Mb/s)	Min	Max	Units
SFP+ Transmitter Jitter Generation				
Total transmitter jitter	9830.40 ⁽¹⁾	–	0.28	UI
	9953.00			
	10312.50			
	10518.75			
	11100.00			
SFP+ Receiver Frequency Jitter Tolerance				
Total receiver jitter tolerance	9830.40 ⁽¹⁾	0.7	–	UI
	9953.00			
	10312.50			
	10518.75			
	11100.00			

Notes:

1. Line rated used for CPRI over SFP+ applications.

Table 65: CPRI Protocol Characteristics

Description	Line Rate (Mb/s)	Min	Max	Units
CPRI Transmitter Jitter Generation				
Total transmitter jitter	614.4	–	0.35	UI
	1228.8	–	0.35	UI
	2457.6	–	0.35	UI
	3072.0	–	0.35	UI
	4915.2	–	0.3	UI
	6144.0	–	0.3	UI
	9830.4	–	Note 1	UI
CPRI Receiver Frequency Jitter Tolerance				
Total receiver jitter tolerance	614.4	0.65	–	UI
	1228.8	0.65	–	UI
	2457.6	0.65	–	UI
	3072.0	0.65	–	UI
	4915.2	0.95	–	UI
	6144.0	0.95	–	UI
	9830.4	Note 1	–	UI

Notes:

1. Tested per SFP+ specification, see Table 64.

Integrated Interface Block for PCI Express Designs Switching Characteristics

More information and documentation on solutions for PCI Express designs can be found at:

<http://www.xilinx.com/technology/protocols/pciexpress.htm>

Table 66: Maximum Performance for PCI Express Designs

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
F _{PIPECLK}	Pipe clock maximum frequency	250.00	250.00	250.00	250.00	MHz
F _{USERCLK}	User clock maximum frequency	500.00	500.00	250.00	250.00	MHz
F _{USERCLK2}	User clock 2 maximum frequency	250.00	250.00	250.00	250.00	MHz
F _{DRPCLK}	DRP clock maximum frequency	250.00	250.00	250.00	250.00	MHz

XADC Specifications

Table 67: XADC Specifications

Parameter	Symbol	Comments/Conditions	Min	Typ	Max	Units
V _{CCADC} = 1.8V ± 5%, V _{REFP} = 1.25V, V _{REFN} = 0V, ADCCLK = 26 MHz, T _j = −40°C to 100°C, Typical values at T _j =+40°C						
ADC Accuracy ⁽¹⁾						
Resolution			12	–	–	Bits
Integral Nonlinearity ⁽²⁾	INL		–	–	±3	LSBs
Differential Nonlinearity	DNL	No missing codes, guaranteed monotonic	–	–	±1	LSBs
Offset Error		Offset calibration enabled	–	–	±6	LSBs
Gain Error		Gain calibration disabled	–	–	±0.5	%
Offset Matching		Offset calibration enabled	–	–	4	LSBs
Gain Matching		Gain calibration disabled	–	–	0.3	%
Sample Rate			0.1	–	1	MS/s
Signal to Noise Ratio ⁽²⁾	SNR	F _{SAMPLE} = 500KS/s, F _{IN} = 20KHz	60	–	–	dB
RMS Code Noise		External 1.25V reference	–	–	2	LSBs
		On-chip reference	–	3	–	LSBs
Total Harmonic Distortion ⁽²⁾	THD	F _{SAMPLE} = 500KS/s, F _{IN} = 20KHz	–	70	–	dB
ADC Accuracy at Extended Temperatures (-55°C to 125°C)						
Resolution			10	–	–	Bits
Integral Nonlinearity ⁽²⁾	INL		–	–	±1	LSB (at 10 bits)
Differential Nonlinearity	DNL	No missing codes, guaranteed monotonic	–	–	±1	
Analog Inputs ⁽³⁾						
ADC Input Ranges		Unipolar operation	0	–	1	V
		Bipolar operation	−0.5	–	+0.5	V
		Unipolar common mode range (FS input)	0	–	+0.5	V
		Bipolar common mode range (FS input)	+0.5	–	+0.6	V
Maximum External Channel Input Ranges		Adjacent channels set within these ranges should not corrupt measurements on adjacent channels	−0.1	–	V _{CCADC}	V
Auxiliary Channel Full Resolution Bandwidth	FRBW		250	–	–	KHz
On-Chip Sensors						
Temperature Sensor Error		T _j = −40°C to 100°C.	–	–	±4	°C
		T _j = −55°C to +125°C	–	–	±6	°C
Supply Sensor Error		Measurement range of V _{CCAUX} 1.8V ±5% T _j = −40°C to +100°C	–	–	±1	%
		Measurement range of V _{CCAUX} 1.8V ±5% T _j = −55°C to +125°C	–	–	±2	%
Conversion Rate ⁽⁴⁾						
Conversion Time - Continuous	t _{CONV}	Number of ADCCLK cycles	26	–	32	Cycles
Conversion Time - Event	t _{CONV}	Number of CLK cycles	–	–	21	Cycles
DRP Clock Frequency	DCLK	DRP clock frequency	8	–	250	MHz
ADC Clock Frequency	ADCCLK	Derived from DCLK	1	–	26	MHz
DCLK Duty Cycle			40	–	60	%

Date	Version	Description
07/25/12	1.6	Updated the descriptions, changed V_{IN} and Note 2 and added Note 4 in Table 1. In Table 2, changed descriptions and notes, removed Note 7, changed GTX transceiver parameters and values and added Note 9. Updated parameters in Table 3. Added Table 4 and Table 5. Changed the typical values for many of the devices in Table 7. Updated LVCMOS12 and the SSTLs in Table 9. Updated many of the specifications in Table 10 and Table 11. Updated speed specification to v1.06 (-3, -2, -2L(1.0V), -1) and v1.05 (-2L(0.9V)) with appropriate changes to Table 14 and Table 15 including production release of the XC7K325T and the XC7K410T in the -2, -2L(1.0V), and -1 speed designations. Added notes and specifications to Table 17 and Table 18. Updated the IOB Pad Input/Output/3-State discussion and changed Table 21 by adding $T_{IOIBUFDISABLE}$. Removed many of the combinatorial delay specifications and T_{CINCK}/T_{CKCIN} from Table 28. Rearranged Table 51 including moving some parameters to Table 1. Added Table 56. Updated Table 57. In Table 59, updated SJ Jitter Tolerance with Stressed Eye section, page 51 and Note 8. Added Note 1, Note 2, and Note 3 to Table 62. Added Note 1 and Note 2 to Table 63, and line rate ranges. Updated Table 64 including adding Note 1. Updated Table 65 including adding Note 1. In Table 67 updated Note 1 and added Note 4. In Table 68, updated T_{POR} and F_{EMCCK}.
09/04/12	1.7	Updated Table 14 and Table 15 for production release of the XC7K160T in the -2, -2L(1.0V), and -1 speed designations.
09/26/12	1.8	In Table 2 , revised V_{CCINT} and V_{CCBRAM} and added Note 2 . Updated Table 14 and Table 15 for production release of the XC7K480T in the -2, -2L(1.0V), and -1 speed designations and the XC7K325T and XC7K410T in the -3 speed designation.
10/10/12	1.9	Updated the $I_{CCINTMIN}$ value for the XC7K355T in Table 7 . Updated Table 14 and Table 15 for production release of the XC7K420T in the -2, -2L(1.0V), and -1 speed designations.
10/25/12	2.0	Updated the AC Switching Characteristics based upon ISE 14.3 v1.07 for the -3, -2, -2L (1.0V), -1 speed specifications, and ISE 14.3 v1.06 for the -2L (0.9V) speed specifications throughout the document. Updated Table 14 and Table 15 for production release of the XC7K355T in the -2, -2L(1.0V), and -1 speed designations. Also updated Table 14 and Table 15 for production release of the XC7K325T and XC7K410T in the -2L (0.9V). Added values for Table 16 -2L (0.9V). Added package skew values to Table 50. In Table 53, increased -1 speed grade (FF package) F_{GTMAX} value from 6.6 Gb/s to 8.0 Gb/s.
10/31/12	2.1	Updated Table 14 and Table 15 for production release of the XC7K70T in the -2, -2L(1.0V), and -1 speed designations.
11/26/12	2.2	Updated Table 14 and Table 15 for production release of -3 speed designation for XC7K70T, XC7K160T, XC7K355T, XC7K420T, and XC7K480T. Removed Note 4 from Table 67 .
12/05/12	2.3	Updated Table 14 and Table 15 for production release of the -2L (0.9V) speed designation for XC7K160T, XC7K420T, and XC7K480T. Updated Note 1 in Table 50 .
12/12/12	2.4	Updated Table 14 and Table 15 for production release of the -2L (0.9V) speed designation for XC7K70T and XC7K355T. Added Internal Configuration Access Port section to Table 68 .